

#### 74AHCT125

**QUADRUPLE 3-STATE BUFFERS OE LOW** 

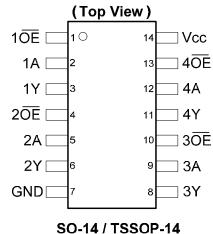
#### Description

The 74AHCT125 provides provides four independent buffer gates with 3-state outputs. Each buffer has a separate enable pin that if driven with a high logic level places the corresponding output in the high impedance state. The device is designed for operation with a power supply range of 4.5V to 5.5V.

#### Features

- Wide Supply Voltage Range from 4.5V to 5.5V
- Inputs Are TTL Voltage Level Compatible
- Outputs Sink or Source 8mA at V<sub>CC</sub> = 4.5V
- CMOS Low Power Consumption
- Schmitt Trigger Action at All Inputs
- ESD Protection Exceeds JESD 22
  - 200-V Machine Model (A115-A)
  - 2000-V Human Body Model (A114-A)
  - Exceeds 1000-V Charged Device Model (C101C) •
- Latch-Up Exceeds 250mA per JESD 78, Class II
- Range of Package Options SO-14 and TSSOP-14
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

## **Pin Assignments**



#### Applications

- General Purpose Logic
- Wide array of products such as:
  - PCs, Networking, Notebooks, Netbooks
  - Computer Peripherals, Hard Drives, CD/DVD ROM
  - TV, DVD, DVR, Set Top Box

Notes:

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.

- 2. See http://www.diodes.com for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

Click here for ordering information, located at the end of datasheet



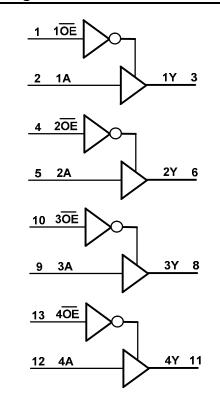
## **Pin Descriptions**

Pin Number	Pin Name	Function
1	10E	Data Enable Input (active low)
2	1A	Data Input
3	1Y	Data Output
4	20E	Data Enable Input (active low)
5	2A	Data Input
6	2Y	Data Output
7	GND	Ground
8	3Y	Data Output
9	3A	Data Input
10	30E	Data Enable Input (active low)
11	4Y	Data Output
12	4A	Data Input
13	40E	Data Enable Input (active low)
14	V <sub>CC</sub>	upply Voltage

# **Function Table**

Inp	Inputs			
ŌE	Α	Y		
L	Н	Н		
L	L	L		
Н	Х	Z		

# Logic Diagram



# Absolute Maximum Ratings (Note 4) (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Symbol	Description	Rating	Unit
ESD HBM Human Body Model ESD Protection		2	KV
ESD CDM	Charged Device Model ESD Protection	1	KV
ESD MM	Machine Model ESD Protection	200	V
V <sub>CC</sub>	Supply Voltage Range	-0.5 to +7.0	V
VI Input Voltage Range		-0.5 to +7.0	V
Input Clamp Current VI < -0.5V		-20	mA
I <sub>OK</sub> Output Clamp Current V <sub>O</sub> < 0V		-20	mA
Іок	Output Clamp Current V <sub>O</sub> > V <sub>CC</sub>	20	mA
Ι <sub>Ο</sub>	Continuous Output Current 0V < V <sub>O</sub> < V <sub>CC</sub>	+/- 25	mA
I <sub>CC</sub>	Continuous Current Through V <sub>CC</sub>	50	mA
I <sub>GND</sub> Continuous Current Through GND		-50	mA
T <sub>J</sub> Operating Junction Temperature		-40 to +150	°C
T <sub>STG</sub> Storage Temperature		-65 to +150	°C
P <sub>TOT</sub>	Total Power Dissipation	500	mW

Note: 4. Stresses beyond the absolute maximum may result in immediate failure or reduced reliability. These are stress values and device operation should be within recommend values.



## Recommended Operating Conditions (Note 5) (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	Supply Voltage	4.5	5.5	V
VI	Input Voltage	0	5.5	V
Vo	Output Voltage	0	Vcc	V
Δt/ΔV	Input Transition Rise or Fall Rate		20	ns/V
T <sub>A</sub>	Operating Free-Air Temperature	-40	+125	°C

Note: 5. Unused inputs should be held at V<sub>CC</sub> or Ground.

## Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Symphol	Devemeter	Test Conditions	V	T <sub>A</sub> = -40°	C to +85°C	T <sub>A</sub> = -40°C	to +125°C	Unit
Symbol	Parameter	Test Conditions	Vcc	Min	Max	Min	Max	Unit
VIH	High-Level Input Voltage		4.5V to 5.5V	2.0		2.0		V
VIL	Low-Level Input Voltage		4.5V to 5.5V		0.8		0.8	V
M	High-Level	Ι <sub>ΟΗ</sub> = -50μΑ	4.5V	4.4		4.4		v
Vон	Output Voltage	I <sub>OH</sub> = -8mA	4.5V	3.80		3.70		v
	Low-Level Output	Ι <sub>ΟL</sub> = 50μΑ	4.5V		0.1		0.1	v
V <sub>OL</sub>	Voltage	I <sub>OL</sub> = 8mA	4.5V		0.44		0.55	v
I <sub>OZ</sub>	Z State Leakage Current	V <sub>O</sub> = 0 to 5.5V	5.5V		±2.5		±10	μA
l <sub>l</sub>	Input Current	V <sub>I</sub> = GND to 5.5V	3.6V		±1		±2	μA
I <sub>CC</sub>	Supply Current	$V_{I} = GND \text{ or } V_{CC}, I_{O} = 0$	3.6V		20		40	μA
ΔI <sub>CC</sub>	Additional Supply Current	One input at $V_{CC}$ -2.1V Other pins at $V_{CC}$ or GND	5.5V		1.35		5	mA

## **Operating Characteristics**

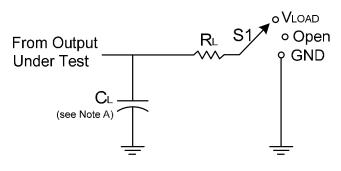
	Parameter	Test Conditions	V <sub>CC</sub> = 5.5V Typ	Unit
C <sub>pd</sub>	Power Dissipation Capacitance per Gate	f = 1MHz	14.8	pF
Ci	Input Capacitance	V <sub>i</sub> = V <sub>CC</sub> – or GND	4.0	pF

# **Switching Characteristics**

Symbol	Parameter	Test Conditions	Г	r <sub>A</sub> = +25°	С	-40°C t	o +85°C	-40°C to	+125°C	Unit
Symbol	Falameter	Test Conditions	Min	Тур.	Max	Min	Max	Min	Max	Unit
	Proposition Delay A to V	Figure 1 C <sub>L</sub> = 15pF	0.5	3.0	5.5	0.5	6.5	0.5	7.0	20
t <sub>PD</sub>	Propagation Delay $A_N$ to $Y_N$	Figure 1 C <sub>L</sub> = 50pF	0.5	4.3	7.5	0.5	8.5	0.5	9.5	ns
	Enable Time $\overline{OE}_N$ to $Y_N$	Figure 1 C <sub>L</sub> = 15pF	0.5	6.7	10.7	0.5	11.0	0.5	11.5	
t <sub>EN</sub>		Figure 1 C <sub>L</sub> = 50pF	0.5	9.8	10.9	0.5	12.1	0.5	12.5	ns
	Disable Time $\overline{OE}_N$ to $Y_N$	Figure 1 C <sub>L</sub> = 15pF	0.5	4.8	6.8	0.5	8.0	0.5	8.5	20
t <sub>DIS</sub>	Disable Time OEN to TN	Figure 1 C <sub>L</sub> = 50pF	0.5	6.5	8.9	0.5	10.0	0.5	11.5	ns

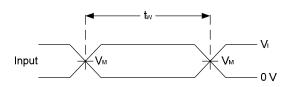


#### **Parameter Measurement Information**

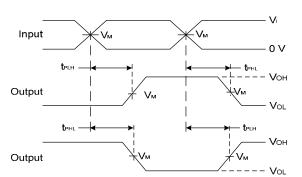


TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	Vload
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

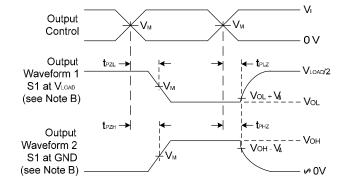
N	Inp	outs	V <sub>M</sub>	V <sub>M</sub>	N N	6		MA
V <sub>cc</sub>	VI	t <sub>r</sub> /t <sub>f</sub>	Inputs	Outputs	VLOAD	CL	ĸL	VΔ
4.5V to 5.5V	3V	≤3ns	1.5V	V <sub>CC</sub> /2	V <sub>CC</sub>	15pF, 50pF	1K	0.3V



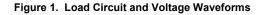
#### Voltage Waveform Pulse Duration







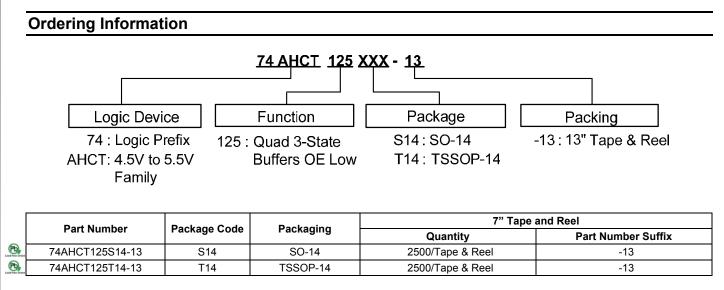
Voltage Waveform Enable and Disable Times Low and High Level Enabling



- Notes: A. Includes test lead and test apparatus capacitance.
  - B. All pulses are supplied at pulse repetition rate  $\leq$  1 MHz.
  - C. Inputs are measured separately one transition per measurement.
  - D.  $t_{\mathsf{PLZ}}$  and  $t_{\mathsf{PHZ}}$  are the same as  $t_{\mathsf{dis}}.$
  - E.  $t_{\text{PZL}}$  and  $t_{\text{PZH}}$  are the same as  $t_{\text{EN0}}.$
  - F.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{PD}$ .

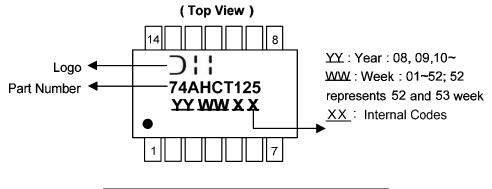
**NEW PRODUCT** 





# **Marking Information**

#### (1) SO-14, TSSOP-14



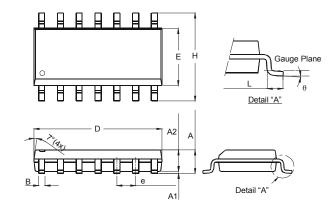
Part Number	Package
74AHCT125S14	SO-14
74AHCT125T14	TSSOP-14



## Package Outline Dimensions (All dimensions in mm.)

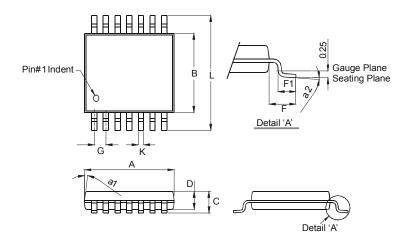
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.

#### Package Type: SO-14



	SO-14						
Dim	Min	Max					
Α	1.47	1.73					
A1	0.10	0.25					
A2 1.45 Typ							
В	0.33	0.51					
D	8.53	8.74					
Е	3.80	3.99					
e	1.27	Тур					
Н	5.80	6.20					
L	0.38	1.27					
θ	<b>θ</b> 0° 8°						
All Dir	nensions	in mm					

#### Package Type: TSSOP-14



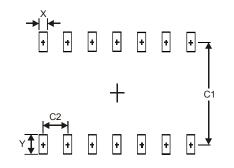
	TSSOP-1	4	
Dim	Min	Max	
a1	7° (4X)		
a2	0°	8°	
Α	4.9	5.10	
В	4.30	4.50	
С		1.2	
D	0.8	1.05	
F	1.00	Тур	
F1	0.45	0.75	
G	0.65	Тур	
Κ	0.19	0.30	
L	6.40	Тур	
All Di	mension	s in mm	



### Suggested Pad Layout

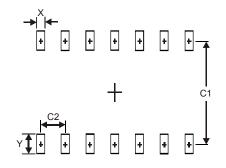
Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.

#### Package Type: SO-14



Dimensions	Value (in mm)
Х	0.60
Y	1.50
C1	5.4
C2	1.27

#### Package Type: TSSOP-14



Dimensions	Value (in mm)
Х	0.45
Y	1.45
C1	5.9
C2	0.65



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